

# INTERNATIONAL STANDARD

**Fibre optic communication subsystem test procedures –  
Part 2-3: Digital systems – Jitter and wander measurements**

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## CONTENTS

FOREWORD.....	5
1 Scope.....	7
1.1 Types of jitter measurements .....	7
1.2 Types of wander measurements .....	7
2 Normative references .....	7
3 Terms and definitions .....	7
4 General considerations.....	11
4.1 Jitter generation .....	11
4.1.1 Timing jitter .....	11
4.1.2 Alignment jitter .....	11
4.1.3 Other effects.....	12
4.2 Effects of jitter on signal quality.....	12
4.3 Jitter tolerance .....	12
4.4 Waiting time jitter .....	13
4.5 Wander .....	14
5 Jitter test procedures.....	14
5.1 General considerations.....	14
5.1.1 Analogue method .....	14
5.1.2 Digital method .....	14
5.2 Common test equipment.....	15
5.3 Safety .....	16
5.4 Fibre optic connections.....	17
5.5 Test sample .....	17
6 Jitter tolerance measurement procedure.....	17
6.1 Purpose .....	17
6.2 Apparatus.....	17
6.3 BER penalty technique .....	17
6.3.1 Equipment connection .....	17
6.3.2 Equipment settings .....	18
6.3.3 Measurement procedure.....	18
6.4 Onset of errors technique .....	18
6.4.1 Equipment connection .....	18
6.4.2 Equipment settings .....	19
6.4.3 Measurement procedure.....	19
6.5 Jitter tolerance stressed eye receiver test .....	20
6.5.1 Purpose.....	20
6.5.2 Apparatus.....	20
6.5.3 Sinusoidal jitter template technique .....	20
7 Measurement of jitter transfer function .....	21
7.1 General.....	21
7.2 Apparatus.....	21
7.3 Basic technique.....	22
7.3.1 Equipment connection .....	22
7.3.2 Equipment settings .....	22
7.3.3 Measurement procedure.....	22
7.4 Analogue phase detector technique.....	23

7.4.1	Equipment connections.....	23
7.4.2	Equipment settings .....	23
7.4.3	Measurement procedure.....	24
7.4.4	Measurement calculations .....	24
8	Measurement of output jitter .....	24
8.1	General.....	24
8.2	Equipment connection .....	24
8.2.1	Equipment settings .....	24
8.2.2	Measurement procedure.....	24
8.2.3	Controlled data.....	25
9	Measurement of systematic jitter .....	25
9.1	Apparatus.....	25
9.2	Basic technique.....	25
9.2.1	Equipment connection .....	25
9.2.2	Equipment settings .....	26
9.2.3	Measurement procedure.....	26
10	BERT scan technique .....	27
10.1	Apparatus.....	29
10.2	Basic technique.....	29
10.2.1	Equipment connection .....	29
10.2.2	Equipment settings .....	29
10.2.3	Measurement process .....	29
11	Jitter separation technique .....	30
11.1	Apparatus.....	31
11.2	Equipment connections .....	31
11.3	Equipment settings.....	31
11.4	Measurement procedure .....	32
11.4.1	Sampling oscilloscope.....	32
11.4.2	Real-time oscilloscope.....	32
12	Measurement of wander .....	33
12.1	Apparatus.....	33
12.2	Basic technique.....	33
12.2.1	Equipment connection .....	33
12.2.2	Equipment settings .....	34
12.2.3	Measurement procedure.....	35
13	Measurement of wander TDEV tolerance.....	35
13.1	Intent.....	35
13.2	Apparatus.....	35
13.3	Basic technique.....	35
13.4	Equipment connection .....	35
13.4.1	Wander TDEV tolerance measurement for the test signal of EUT .....	35
13.4.2	Wander TDEV tolerance measurement for timing reference signal of EUT .....	36
13.5	Equipment settings.....	36
13.6	Measurement procedure.....	37
14	Measurement of wander TDEV transfer .....	37
14.1	Apparatus.....	37
14.2	Equipment connection .....	37

14.2.1 Wander TDEV transfer measurement for the test signal of EUT .....	37
14.2.2 Wander TDEV transfer measurement for timing reference signal of EUT .....	37
14.3 Equipment settings .....	38
14.4 Measurement procedure .....	38
15 Test results .....	38
15.1 Mandatory information .....	38
15.2 Available information .....	39
Bibliography .....	40
Figure 1 – Jitter generation .....	11
Figure 2 – Example of jitter tolerance .....	13
Figure 3 – Jitter and wander generator .....	15
Figure 4 – Jitter and wander measurement .....	16
Figure 5 – Jitter stress generator .....	16
Figure 6 – Jitter tolerance measurement configuration: bit error ratio (BER) penalty technique .....	18
Figure 7 – Jitter tolerance measurement configuration: Onset of errors technique .....	19
Figure 8 – Equipment configuration for stressed eye tolerance test .....	20
Figure 9 – Measurement of jitter transfer function: basic technique .....	22
Figure 10 – Measurement of Jitter transfer: analogue phase detector technique .....	23
Figure 11 – Output jitter measurement .....	25
Figure 12 – Systematic jitter measurement configuration: basic technique .....	26
Figure 13 – Measurement of the pattern-dependent phase sequence $\xi_i$ .....	27
Figure 14 – BERT scan bathtub curves (solid line for low jitter, dashed line for high jitter) .....	28
Figure 15 – Equipment setup for the BERT scan .....	29
Figure 16 – Dual Dirac jitter model .....	31
Figure 17 – Equipment setup for jitter separation measurement .....	31
Figure 18 – Measurement of time interval error .....	32
Figure 19 – Synchronized wander measurement configuration .....	34
Figure 20 – Non-synchronized wander measurement configuration .....	34
Figure 21 – Wander TDEV tolerance measurement configuration for the test signal of EUT .....	36
Figure 22 – Wander TDEV tolerance measurement configuration for the timing signal of EUT .....	36
Figure 23 – Wander TDEV transfer measurement configuration for the test signal of EUT .....	37
Figure 24 – Wander TDEV transfer measurement configuration for the timing signal of EUT .....	38

## INTERNATIONAL ELECTROTECHNICAL COMMISSION

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**FIBRE OPTIC COMMUNICATION SUBSYSTEM  
TEST PROCEDURES –**
**Part 2-3: Digital systems –  
Jitter and wander measurements**

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International Standard IEC 61280-2-3 has been prepared by subcommittee 86C: Fibre optic systems and active devices, of IEC technical committee 86: Fibre optics.

The text of this standard is based on the following documents:

FDIS	Report on voting
86C/885/FDIS	86C/905/RVD

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

A list of all parts of the IEC 61280-2 series, published under the general title *Fibre optic communication subsystem test procedures – Digital systems*, can be found on the IEC website.

The committee has decided that the contents of this publication will remain unchanged until the maintenance result date indicated on the IEC web site under "<http://webstore.iec.ch>" in the data related to the specific publication. At this date, the publication will be

- reconfirmed;
- withdrawn;
- replaced by a revised edition, or
- amended.

A bilingual version may be published at a later date.

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## FIBRE OPTIC COMMUNICATION SUBSYSTEM TEST PROCEDURES –

### Part 2-3: Digital systems – Jitter and wander measurements

#### 1 Scope

This part of IEC 61280 specifies methods for the measurement of the jitter and wander parameters associated with the transmission and handling of digital signals.

##### 1.1 Types of jitter measurements

This standard covers the measurement of the following types of jitter parameters:

- a) jitter tolerance
  - 1) sinusoidal method
  - 2) stressed eye method
- b) jitter transfer function
- c) output jitter
- d) systematic jitter
- e) jitter separation

##### 1.2 Types of wander measurements

This standard covers the measurement of the following types of wander parameters:

- a) non-synchronized wander
- b) TDEV tolerance
- c) TDEV transfer
- d) synchronized wander

#### 2 Normative references

The following referenced documents are indispensable for the application of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 60825-1, *Safety of laser products – Part 1: Equipment classification and requirements*

ITU-T Recommendation G.813, *Timing characteristics of SDH equipment slave clocks (SEC)*

#### 3 Terms and definitions

For the purposes of this document, the following terms and definitions apply.

NOTE See also IEC 61931.

### 3.1

#### **jitter**

the short-term, non-cumulative, variation in time of the significant instances of a digital signal from their ideal position in time. Short-term variations in this context are jitter components with a repetition frequency equal to or exceeding 10 Hz

### 3.2

#### **jitter amplitude**

the deviation of the significant instance of a digital signal from its ideal position in time

NOTE For the purposes of this standard the jitter amplitude is expressed in terms of the unit interval (UI). It is recognized that jitter amplitude may also be expressed in units of time.

### 3.3

#### **unit interval (UI)**

the shortest interval between two equivalent instances in ideal positions in time. In practice this is equivalent to the ideal timing period of the digital signal

### 3.4

#### **jitter frequency**

the rate of variation in time of the significant instances of a digital signal relative to their ideal position in time. Jitter frequency is expressed in Hertz (Hz)

### 3.5

#### **jitter bandwidth**

the jitter frequency at which the jitter amplitude has decreased by 3dB relative to its maximum value

### 3.6

#### **alignment jitter**

jitter created when the timing of a data signal is recovered from the signal itself

### 3.7

#### **timing jitter**

jitter present on a timing source

### 3.8

#### **systematic jitter**

jitter components which are not random and have a predictable rate of occurrence. Systematic jitter in a digital signal results from regularly recurring features in the digital signal, such as frame alignment data, and justification control data. This is sometimes referred to as deterministic jitter and is composed of periodic uncorrelated jitter and data dependent jitter

### 3.9

#### **periodic uncorrelated jitter**

a form of systematic jitter that occurs at a regular rate, but is uncorrelated to the data when the data pattern repeats. Periodic uncorrelated jitter will be the same independent of which edge in a pattern is observed over time. Sources of periodic uncorrelated jitter include switching power supplies phase modulating reference clocks or any form of periodic phase modulation of clocks that control data rates

### 3.10

#### **inter-symbol interference jitter**

caused by bandwidth limitations in transmission channels. If the channel bandwidth is low, signal transitions may not reach full amplitude before transitioning to a different logic state. Starting at a level closer to the midpoint between logic states, the time at which the signal edge then crosses a specific amplitude threshold can be early compared to consecutive identical digits which have reached full amplitude and then switch to the other logic state

**3.11****duty cycle distortion**

occurs when the duration of a logic 1 (0-1-0) is different from the duration of a logic 0 (1-0-1). For example, if the logic 1 has a longer duration, rising edges will occur early relative to falling edges, compared to their ideal locations in time

**3.12****data dependent jitter**

represents jitter that is correlated to specific bits in a repeating data pattern. That is, when a data pattern repeats, the jitter on any given signal edge will manifest itself in the same way for any repetition of the pattern. It is due to either duty cycle distortion and/or inter-symbol interference

**3.13****waiting time jitter**

applies to plesiochronous multiplexing and is defined as the jitter caused by the varying delay between the demand for justification and its execution

**3.14****jitter tolerance**

maximum jitter amplitude that a digital receiver can accept for a given penalty or alternatively without the addition of a given number of errors to the digital signal. The maximum jitter amplitude tolerated is generally dependent on the frequency of the jitter

**3.15****jitter generation**

process of adding jitter impairment to a data signal

**3.16****input jitter**

magnitude of the jitter occurring at a hierarchical interface or the input port of equipment or a device

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**3.17****output jitter**

magnitude of the jitter occurring at a hierarchical interface or the output port of equipment or a device

**3.18****jitter transfer**

amount of jitter transferred from the input to the output of an equipment or device. It is usually expressed as a ratio (in dB) of the output jitter to the input jitter

**3.19****total jitter**

the summation (or convolution) of deterministic and random jitter. Total jitter is expressed as a peak value

**3.20****jitter bathtub curve**

display of bit-error-ratio as a function of the time location of the BERT error detector sampling point. The resulting curve is then a display of the probability that a data edge will be misplaced at or beyond a specific location (closer to the centre of a bit) within a unit interval

**3.21****wander**

long-term, non-cumulative, variation in time of the significant instances of a digital signal from their ideal position in time. Long-term variations in this context are jitter components with a repetition frequency less than 10 Hz

NOTE For the purpose of this document, the wander amplitude is expressed in units of time (s). It is recognised that wander amplitude may also be expressed in terms of unit interval (UI).

**3.22**  
**time interval error**  
**TIE**

difference between the measure of a time interval as provided by a clock and the measure of that same time interval as provided by a reference clock. Mathematically, the time interval error function TIE ( $t; \tau$ ) can be expressed as:

$$TIE(t; \tau) = [T(t + \tau) - T(t)] - [T_{ref}(t + \tau) - T_{ref}(t)] = x(t + \tau) - x(t) \quad (1)$$

where  $\tau$  is the time interval, usually called observation interval

**3.23**  
**maximum time interval error**  
**MTIE**

maximum peak-to-peak delay variation of a given timing signal with respect to an ideal timing signal within an observation time ( $\tau = n\tau_0$ ) for all observation times of that length within the measurement period ( $T$ ). It is estimated using the following formula:

$$MTIE(n\tau_0) \cong \max_{1 \leq k \leq N-n} \left[ \max_{k \leq i \leq k+n} x_i - \min_{k \leq i \leq k+n} x_i \right] \quad n = 1, 2, \dots, N-1 \quad (2)$$

**3.24**  
**time deviation**  
**TDEV or  $\sigma_x$**

measure of the expected time variation of a signal as a function of integration time. TDEV can also provide information about the spectral content of the phase (or time) noise of a signal. TDEV is in units of time. Based on the sequence of time error samples, TDEV is estimated using the following calculation:

$$TDEV(n\tau_0) \cong \sqrt{\frac{1}{6n^2(N-3n+1)} \sum_{j=1}^{N-3n+1} \left[ \sum_{i=j}^{n+j-1} (x_{i+2n} - 2x_{i+n} + x_i) \right]^2} \quad n = 1, 2, \dots, \text{int} \left( \frac{N}{3} \right) \quad (3)$$

where

- $x_i$  denotes time error samples;
- $N$  denotes the total number of samples;
- $\tau_0$  denotes the time error-sampling interval;
- $\tau$  denotes the integration time, the independent variable of TDEV;
- $n$  denotes the number of sampling intervals within the integration time  $t$ .

**3.25**  
**bit error ratio**  
**BER**

number of bits received in error as a ratio of the total number of bits received

**3.26**  
**errored second**

time of 1 s duration that contains one or more digital errors in a data stream